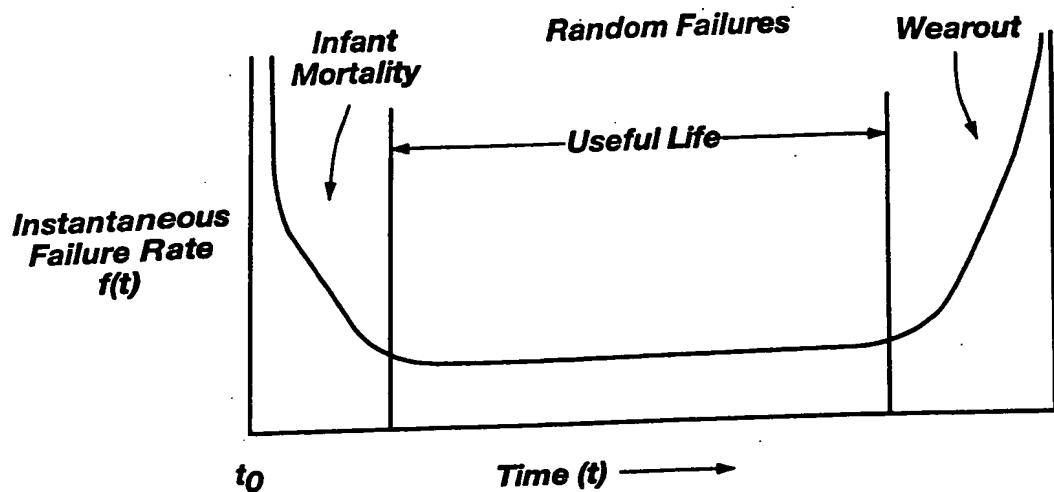
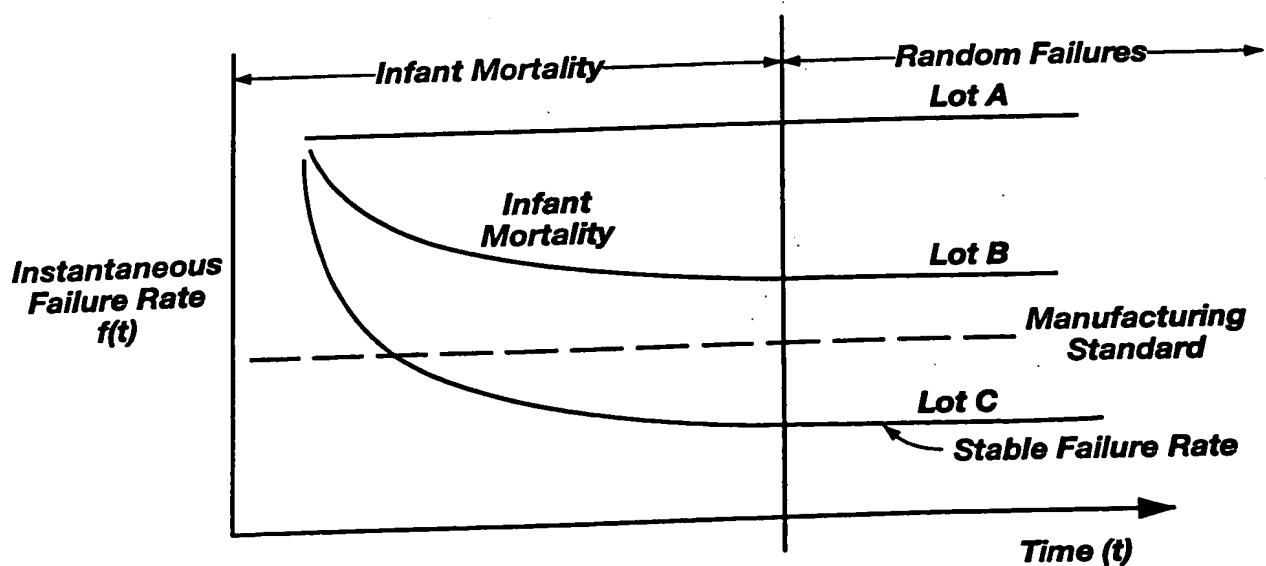


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**Fig. 1**  
(PRIOR ART)



**Fig. 2**  
(PRIOR ART)

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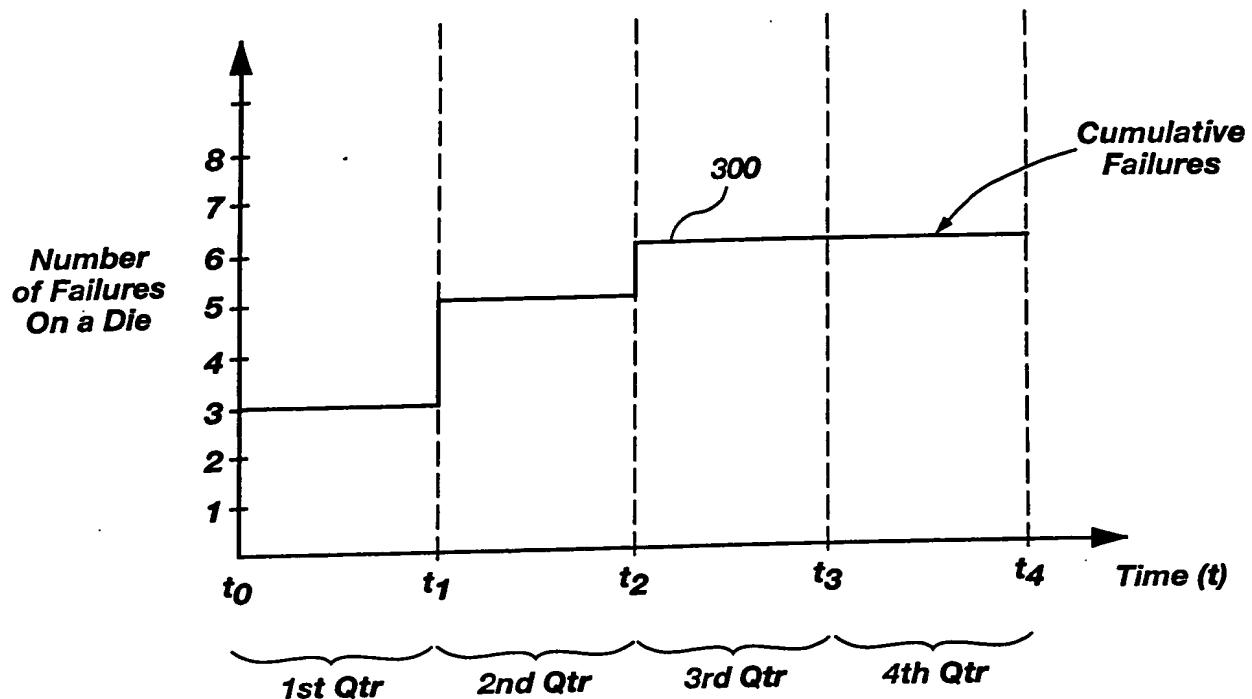


Fig. 3

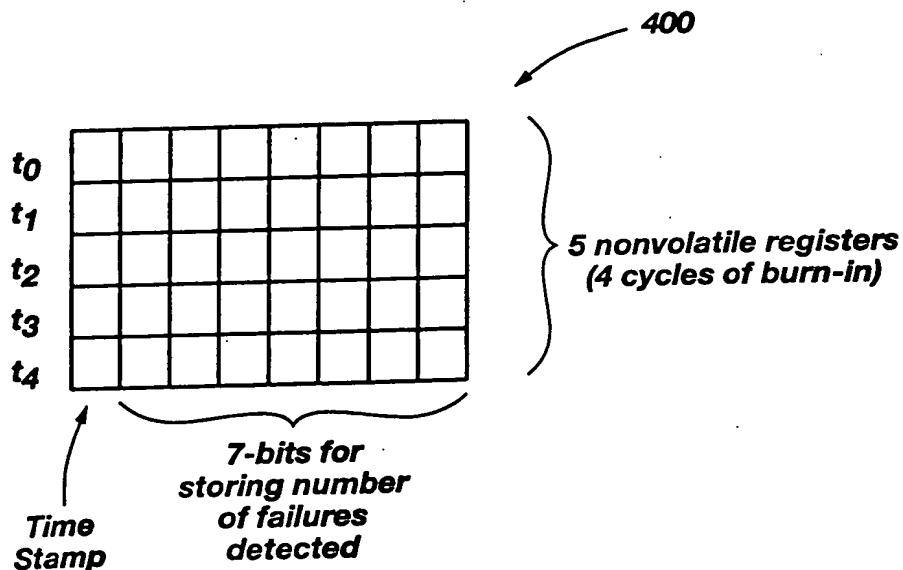


Fig. 4

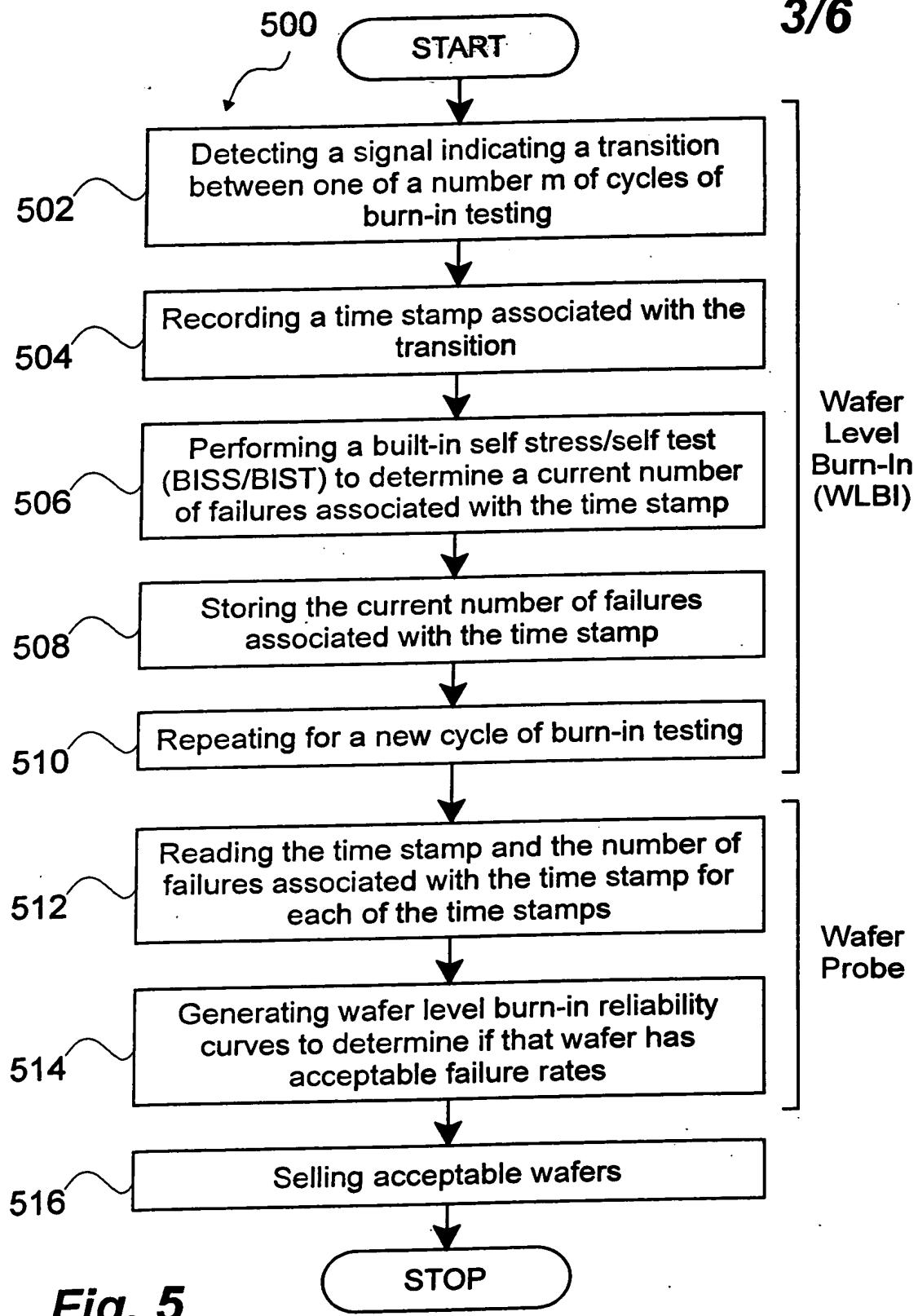
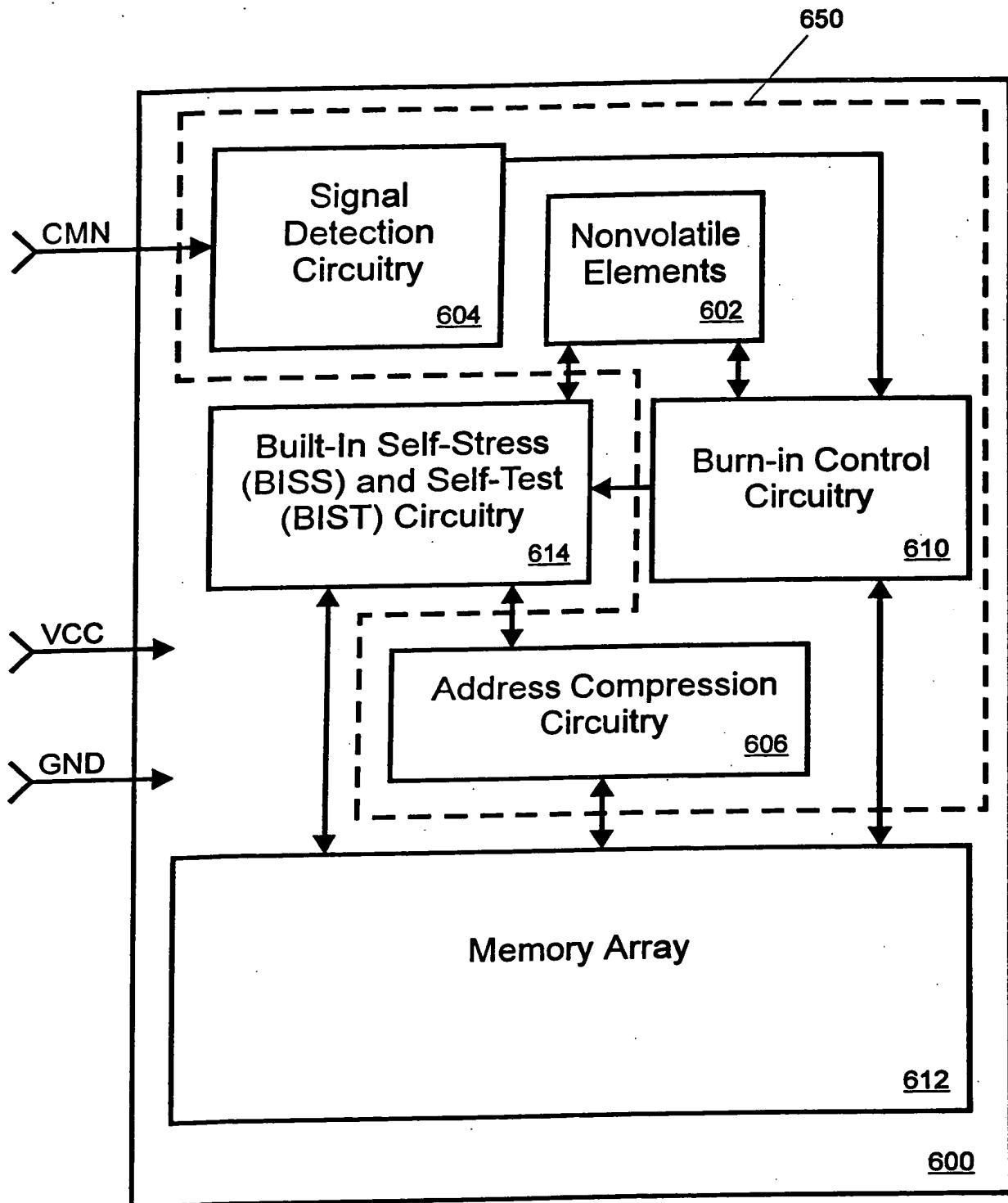


Fig. 5

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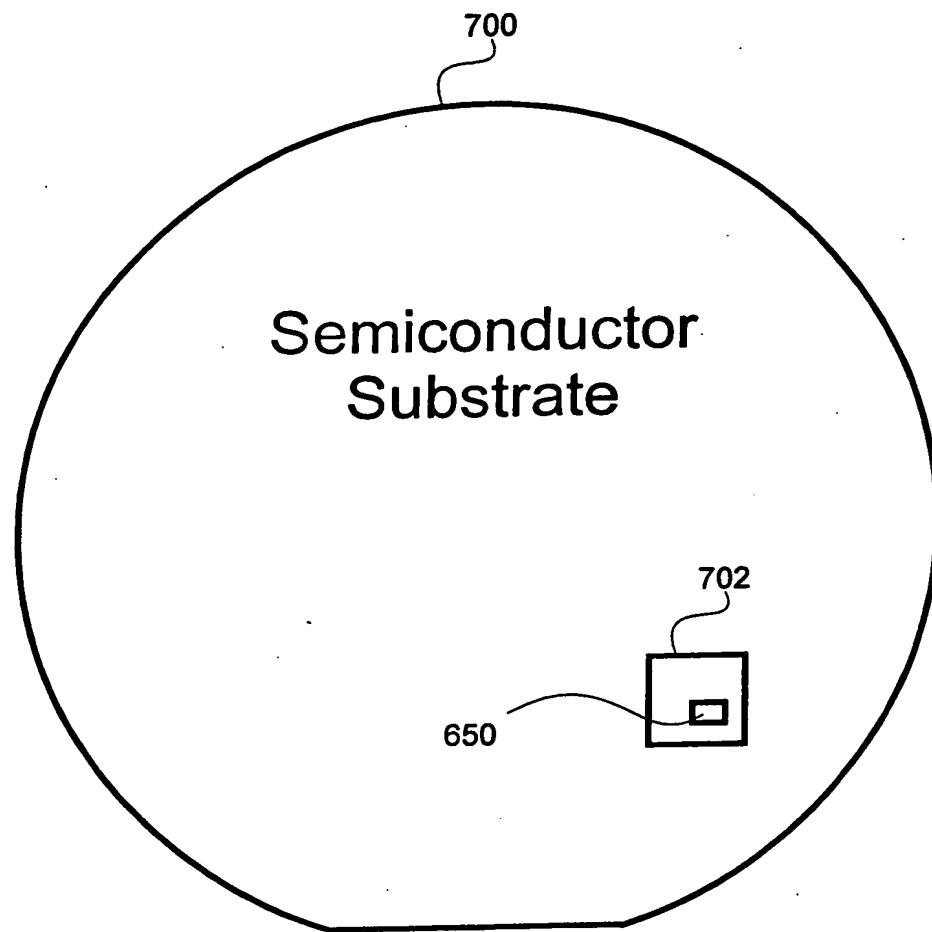


*Fig. 6*

TITLE: METHOD AND APPARATUS FOR DETERMINING BURN-  
IN RELIABILITY FROM WAFER LEVEL BURN-IN

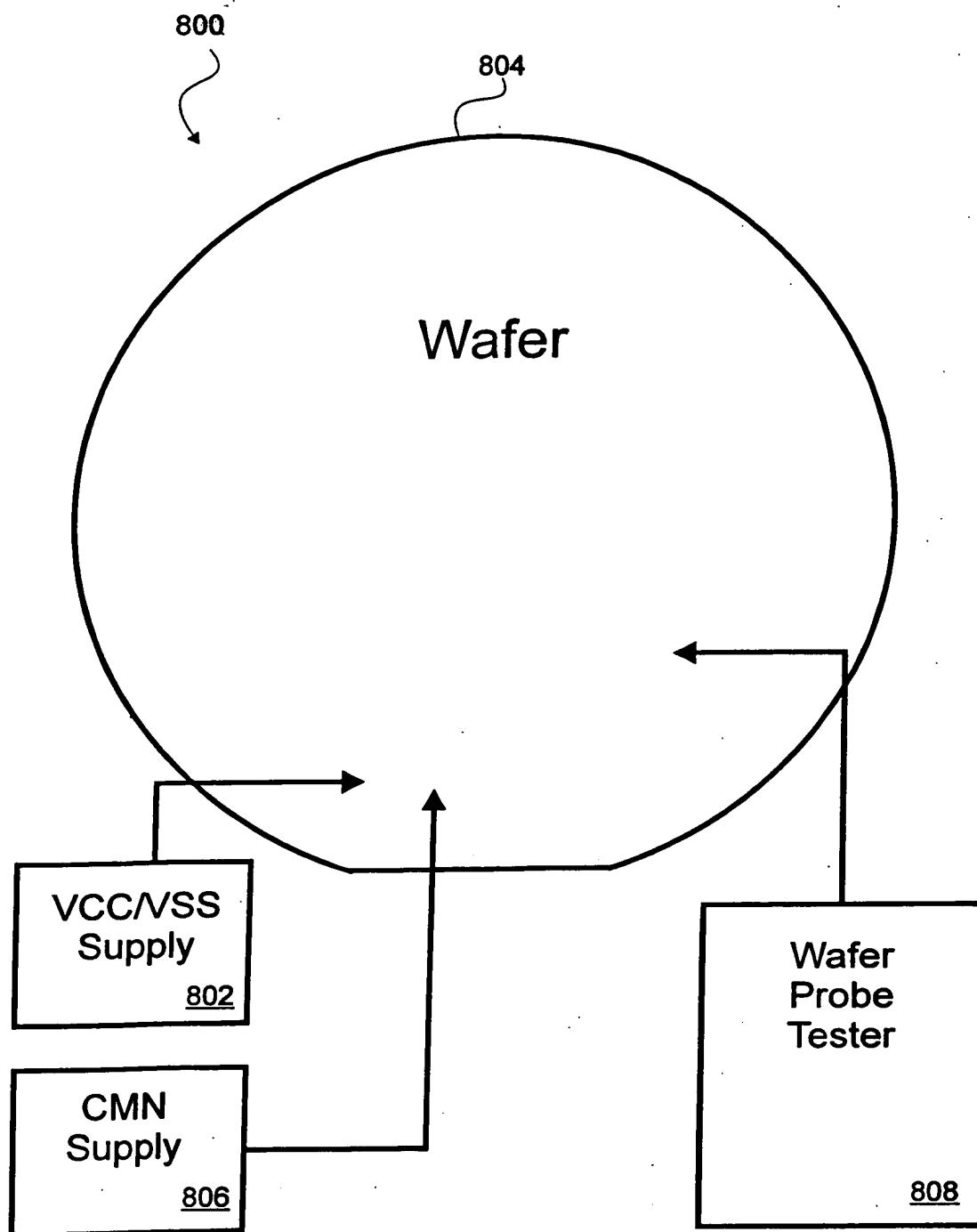
Inventor: Kenneth W. Marr  
Docket No.: 2269-5153.1US

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***Fig. 7***

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*Fig. 8*